Welcome to the 2003 Asian Test Symposium (ATS’03), the 12th in a series that has evolved as one of the most important international events held in Asia on testing. This symposium is a forum for researchers and engineers from all countries and regions in the world to present and share state-of-the-art ideas and technologies in testing.

The academic Program Committee of ATS’03 consists of 60 members from 10 countries and Regions in the world. These members have contributed greatly in promoting paper submissions, reviewing the submitted manuscripts, and finalizing the academic program. This year we received 141 paper submissions from 20 countries and regions. Among them, 58 from Mainland China, 25 from USA, 17 from Japan, 6 from Taiwan, 4 from each of Sweden, Germany and Iran, 3 from France, 2 from Hong Kong and the Netherlands, and 1 each from Singapore, Korea, Australia, Canada, Poland, Brazil, Italy, Kuwait, and Saudi Arabia.

Each paper was reviewed respectively by three reviewers from North America, Japan, and the rest of the world. Due to the unexpected effect of SARS, we have to cancel the Program Committee meeting in Beijing, instead, a collection of review results was emailed to each member of the Program Committee. Based on the reviewers’ judgments, ratings, and comments, 47 submissions were accepted as regular papers with 6 pages, 41 submissions were accepted as short papers with 4 pages. These 88 papers were allocated into 26 regular sessions for oral presentation, which cover most of the key areas in testing. Besides, 9 papers were selected for poster. Based on the evaluations of reviewers, attendees, and an invited panel of judges, an ATS’03 best paper will be selected. The best paper award of ATS’03 will be presented at ATS’04 in Taiwan.

Two keynotes entitled “Outstanding Challenges in Testing Nanotechnology Based Integrated Circuits” and “Leveraging Infrastructure IP for Yield and Reliability” will address the challenges in testing from the academic and industry points of views, respectively. In addition, a half-day tutorial “System-on-Chip: Embedded Test in Practice” will be offered.

Finally, we would like to thank members of ATS Steering Committee for their kind advice and support. Also, we express our gratitude to the authors for submitting their works to ATS’03 and to the Program Committee members and reviewers for their contributions and effort to produce an excellent technical program.

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